



## Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery ( $Q_{rr}$ )
- Halogen free, RoHS compliant

## Benefits

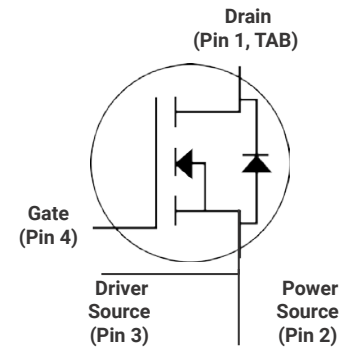
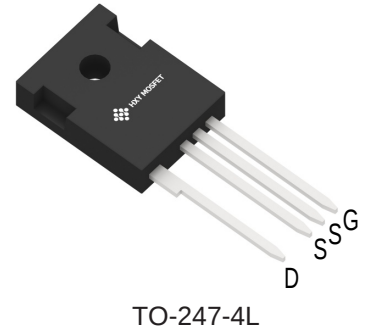
- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

## Applications

- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies



| Ordering Part Number | Package  | Qty(PCS) |
|----------------------|----------|----------|
| SCT040W120G3-4       | TO247-4L | 30       |



## Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

| Symbol         | Parameter                                  | Value       | Unit             | Test Conditions                                        |
|----------------|--------------------------------------------|-------------|------------------|--------------------------------------------------------|
| $V_{DSmax}$    | Drain - Source Voltage                     | 1200        | V                | $V_{GS} = 0\text{ V}$ , $I_D = 100\text{ }\mu\text{A}$ |
| $V_{GSmax}$    | Gate - Source Voltage (dynamic)            | -10/+25     | V                | AC ( $f > 1\text{ Hz}$ )                               |
| $V_{GSop}$     | Gate - Source Voltage (static)             | -5/+20      | V                | Static                                                 |
| $I_D$          | Continuous Drain Current                   | 78          | A                | $V_{GS} = 15\text{ V}$ , $T_c = 25^\circ\text{C}$      |
|                |                                            | 57          |                  | $V_{GS} = 15\text{ V}$ , $T_c = 100^\circ\text{C}$     |
| $I_{D(pulse)}$ | Pulsed Drain Current                       | TBD         | A                | Pulse width $t_p$ limited by $T_{jmax}$                |
| $P_D$          | Power Dissipation                          | 405         | W                | $T_c = 25^\circ\text{C}$ , $T_j = 175^\circ\text{C}$   |
| $T_j, T_{stg}$ | Operating Junction and Storage Temperature | -40 to +175 | $^\circ\text{C}$ |                                                        |
| $T_L$          | Solder Temperature                         | 260         | $^\circ\text{C}$ | 1.6mm (0.063") from case for 10s                       |



**Electrical Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

| Symbol        | Parameter                                 | Min. | Typ. | Max. | Unit          | Test Conditions                                                                                                                                                 | Note         |
|---------------|-------------------------------------------|------|------|------|---------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------|--------------|
| $V_{(BR)DSS}$ | Drain-Source Breakdown Voltage            | 1200 |      |      | V             | $V_{GS} = 0\text{ V}, I_D = 100\text{ }\mu\text{A}$                                                                                                             |              |
| $V_{GS(th)}$  | Gate Threshold Voltage                    | 2.0  | 2.5  | 4.0  | V             | $V_{DS} = V_{GS}, I_D = 10\text{ mA}$                                                                                                                           | Fig. 11      |
|               |                                           |      | 1.5  |      | V             | $V_{DS} = V_{GS}, I_D = 10\text{ mA}, T_J = 175^\circ\text{C}$                                                                                                  |              |
| $I_{DSS}$     | Zero Gate Voltage Drain Current           |      | 1    | 50   | $\mu\text{A}$ | $V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}$                                                                                                                   |              |
| $I_{GSS}$     | Gate-Source Leakage Current               |      | 10   | 200  | nA            | $V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$                                                                                                                     |              |
|               |                                           | -200 | -10  |      | nA            | $V_{GS} = -10\text{ V}, V_{DS} = 0\text{ V}$                                                                                                                    |              |
| $R_{DS(on)}$  | Drain-Source On-State Resistance          |      | 40   | 50   | m $\Omega$    | $V_{GS} = 20\text{ V}, I_D = 40\text{ A}$                                                                                                                       | Fig. 4, 5, 6 |
|               |                                           |      | 59   |      |               | $V_{GS} = 20\text{ V}, I_D = 40\text{ A}, T_J = 175^\circ\text{C}$                                                                                              |              |
| $g_{fs}$      | Transconductance                          |      | 10.4 |      | S             | $V_{DS} = 20\text{ V}, I_{DS} = 40\text{ A}$                                                                                                                    | Fig. 7       |
|               |                                           |      | 7.7  |      |               | $V_{DS} = 20\text{ V}, I_{DS} = 40\text{ A}, T_J = 175^\circ\text{C}$                                                                                           |              |
| $C_{iss}$     | Input Capacitance                         |      | 2101 |      | pF            | $V_{GS} = 0\text{ V}, V_{DS} = 1000\text{ V}$<br>$f = 100\text{ kHz}$<br>$V_{AC} = 25\text{ mV}$                                                                | Fig. 17, 18  |
| $C_{oss}$     | Output Capacitance                        |      | 161  |      |               |                                                                                                                                                                 |              |
| $C_{rss}$     | Reverse Transfer Capacitance              |      | 14   |      |               |                                                                                                                                                                 |              |
| $E_{oss}$     | $C_{oss}$ Stored Energy                   |      | 90   |      |               |                                                                                                                                                                 | Fig. 16      |
| $E_{ON}$      | Turn-On Switching Energy (SiC Diode FWD)  |      | 1100 |      | $\mu\text{J}$ | $V_{DS} = 800\text{ V}, V_{GS} = -5\text{ V}/+20\text{ V}, I_D = 40\text{ A},$<br>$R_{G(ext)} = 2.5\Omega, L = 100\text{ }\mu\text{H}, T_J = 175^\circ\text{C}$ | Fig. 26      |
| $E_{OFF}$     | Turn Off Switching Energy (SiC Diode FWD) |      | 900  |      |               |                                                                                                                                                                 |              |
| $t_{d(on)}$   | Turn-On Delay Time                        |      | 22   |      | ns            | $V_{DD} = 800\text{ V}, V_{GS} = -5\text{ V}/20\text{ V}$<br>$R_{G(ext)} = 2.5\Omega, I_D = 40\text{ A}$<br>Timing relative to $V_{DS}$                         | Fig. 27      |
| $t_r$         | Rise Time                                 |      | 49   |      |               |                                                                                                                                                                 |              |
| $t_{d(off)}$  | Turn-Off Delay Time                       |      | 71   |      |               |                                                                                                                                                                 |              |
| $t_f$         | Fall Time                                 |      | 23   |      |               |                                                                                                                                                                 |              |
| $R_{G(int)}$  | Internal Gate Resistance                  |      | 1.7  |      | $\Omega$      | $f = 1\text{ MHz}, V_{AC} = 25\text{ mV}$                                                                                                                       |              |
| $Q_{gs}$      | Gate to Source Charge                     |      | 33   |      | nC            | $V_{DS} = 800\text{ V}, V_{GS} = -5\text{ V}/20\text{ V}$<br>$I_D = 40\text{ A}$                                                                                | Fig. 12      |
| $Q_{gd}$      | Gate to Drain Charge                      |      | 51   |      |               |                                                                                                                                                                 |              |
| $Q_g$         | Total Gate Charge                         |      | 131  |      |               |                                                                                                                                                                 |              |

**Reverse Diode Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

| Symbol        | Parameter                        | Typ. | Max. | Unit | Test Conditions                                                                                                                          | Note          |
|---------------|----------------------------------|------|------|------|------------------------------------------------------------------------------------------------------------------------------------------|---------------|
| $V_{SD}$      | Diode Forward Voltage            | 4.1  |      | V    | $V_{GS} = -5\text{ V}, I_{SD} = 20\text{ A}, T_J = 25^\circ\text{C}$                                                                     | Fig. 8, 9, 10 |
|               |                                  | 3.5  |      | V    | $V_{GS} = -5\text{ V}, I_{SD} = 20\text{ A}, T_J = 175^\circ\text{C}$                                                                    |               |
| $I_S$         | Continuous Diode Forward Current |      | 83   | A    | $V_{GS} = -4\text{ V}, T_c = 25^\circ\text{C}$                                                                                           | Note 1        |
| $I_{S,pulse}$ | Diode pulse Current              |      | TBD  | A    | $V_{GS} = -4\text{ V}, \text{pulse width } t_p \text{ limited by } T_{jmax}$                                                             | Note 1        |
| $t_{rr}$      | Reverse Recover time             | 56   |      | ns   | $V_{GS} = -5\text{ V}, I_{SD} = 40\text{ A}, V_R = 800\text{ V}$<br>$\text{dif/dt} = 2250\text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$ | Note 1        |
| $Q_{rr}$      | Reverse Recovery Charge          | 508  |      | nC   |                                                                                                                                          |               |
| $I_{rrm}$     | Peak Reverse Recovery Current    | 18   |      | A    |                                                                                                                                          |               |

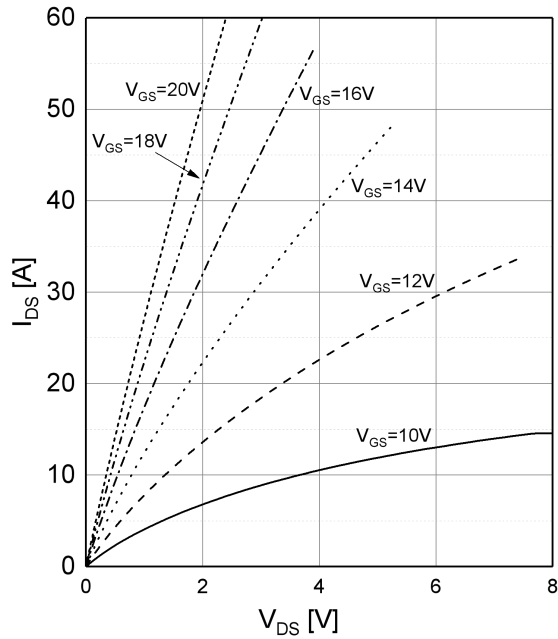
**Thermal Characteristics**

| Symbol          | Parameter                                   | Typ. | Unit                      | Test Conditions | Note    |
|-----------------|---------------------------------------------|------|---------------------------|-----------------|---------|
| $R_{\theta JC}$ | Thermal Resistance from Junction to Case    | 0.25 | $^\circ\text{C}/\text{W}$ |                 | Fig. 21 |
| $R_{\theta JA}$ | Thermal Resistance From Junction to Ambient | 40   |                           |                 |         |



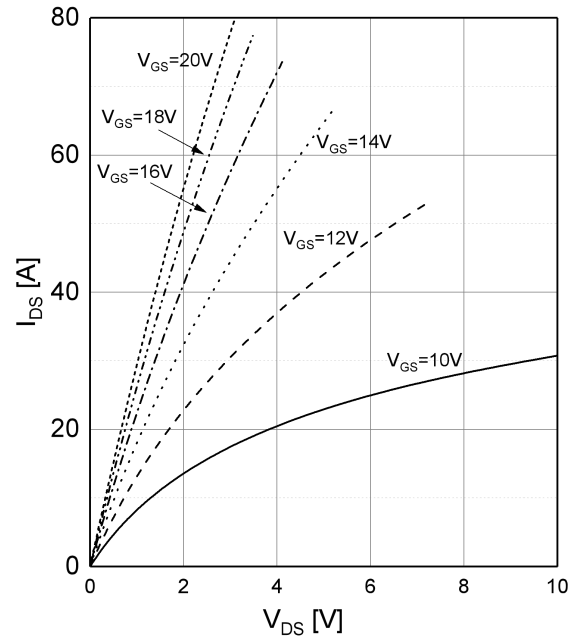
Output characteristics

$$I_{DS}=f(V_{DS}), T_J=-55^{\circ}\text{C}$$



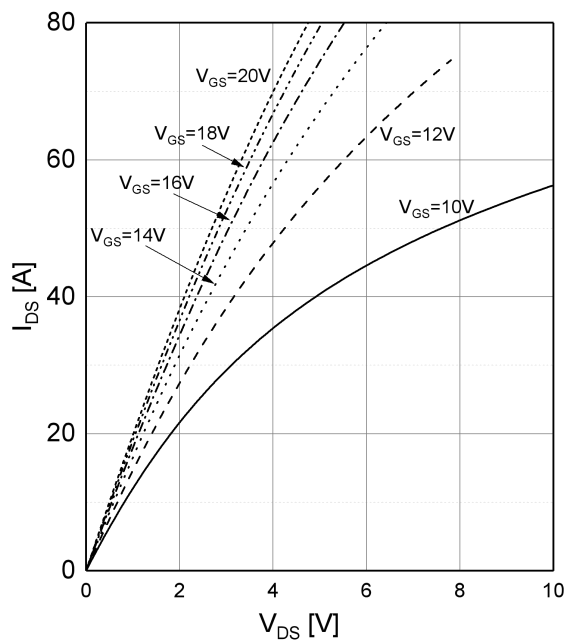
Output characteristics

$$I_{DS}=f(V_{DS}), T_J=25^{\circ}\text{C}$$



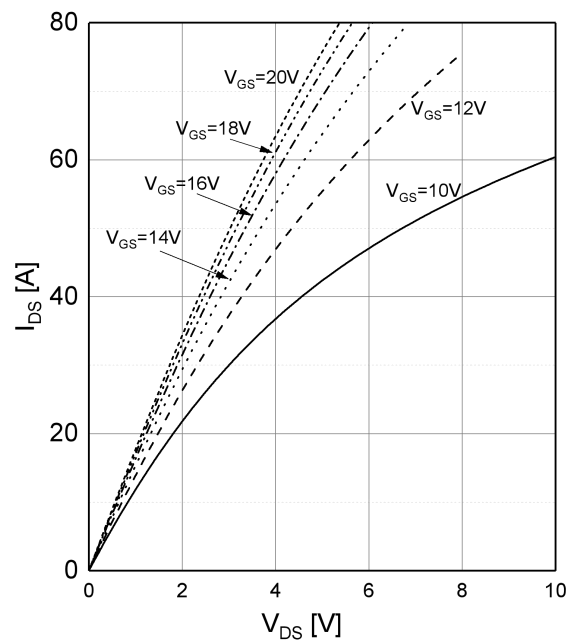
Output characteristics

$$I_{DS}=f(V_{DS}), T_J=150^{\circ}\text{C}$$



Output characteristics

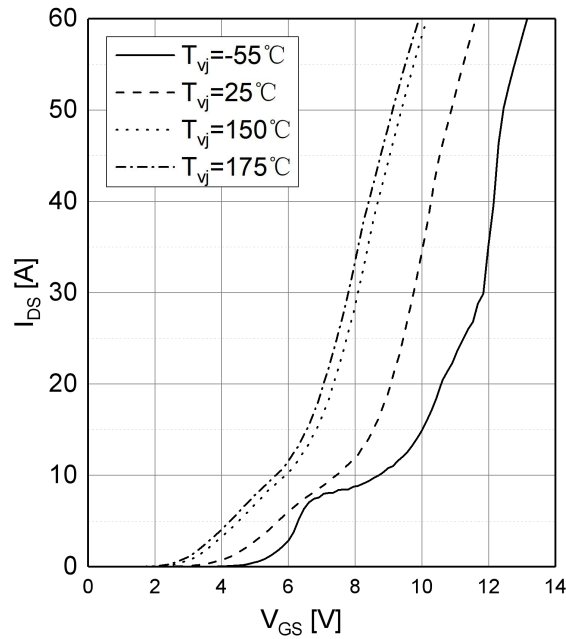
$$I_{DS}=f(V_{DS}), T_J=175^{\circ}\text{C}$$





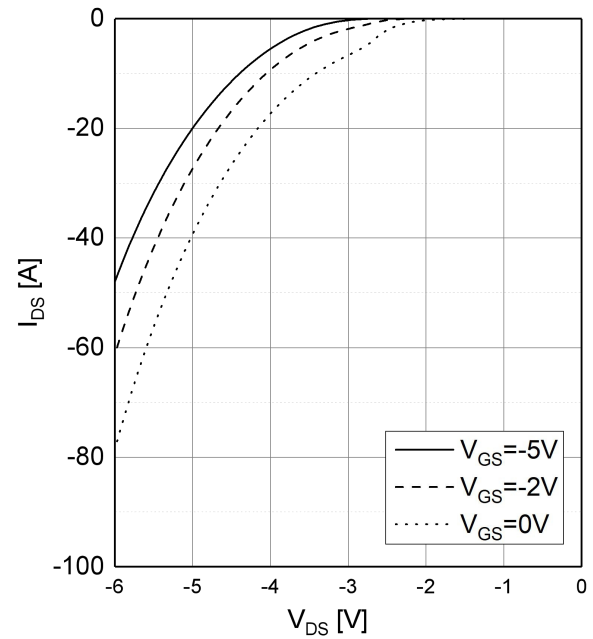
Transfer Characteristics

$$I_{DS}=f(V_{GS}), V_{DS}=20V$$



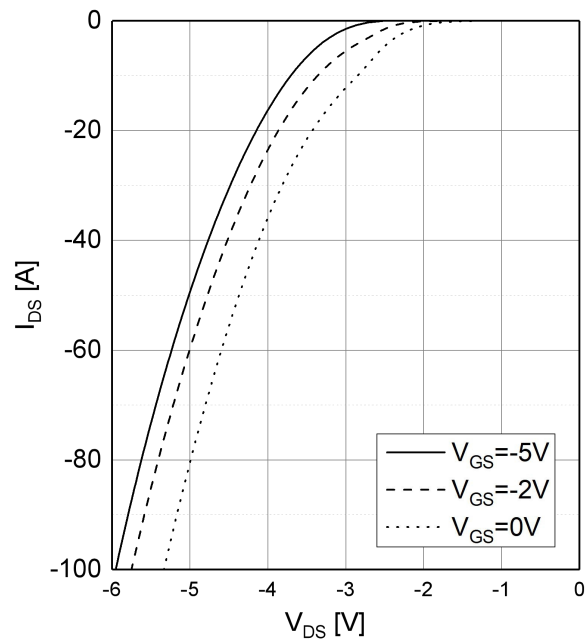
Body Diode Characteristics

$$I_{DS}=f(V_{DS}), T_J=-55^{\circ}C$$



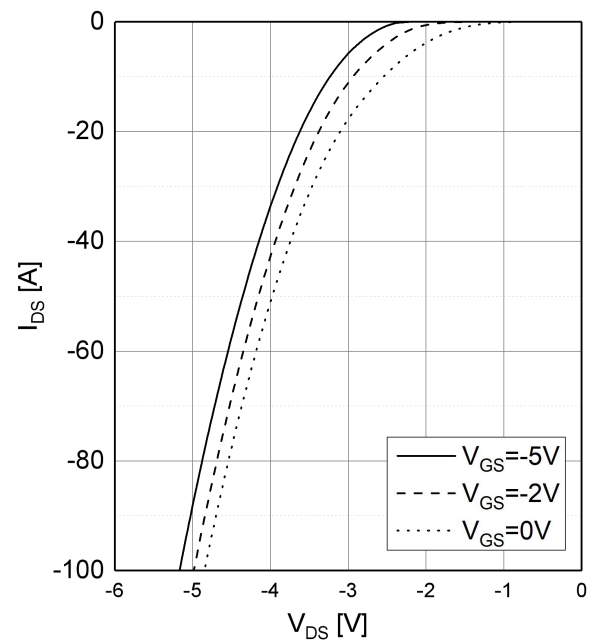
Body Diode Characteristics

$$I_{DS}=f(V_{DS}), T_J=25^{\circ}C$$



Body Diode Characteristics

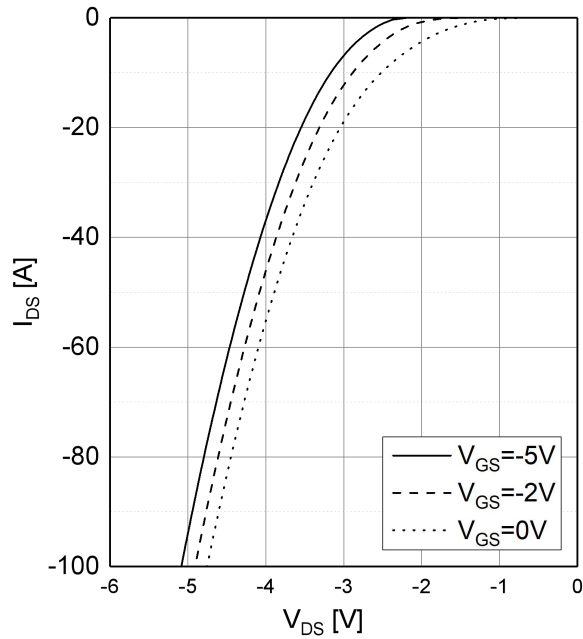
$$I_{DS}=f(V_{DS}), T_J=150^{\circ}C$$





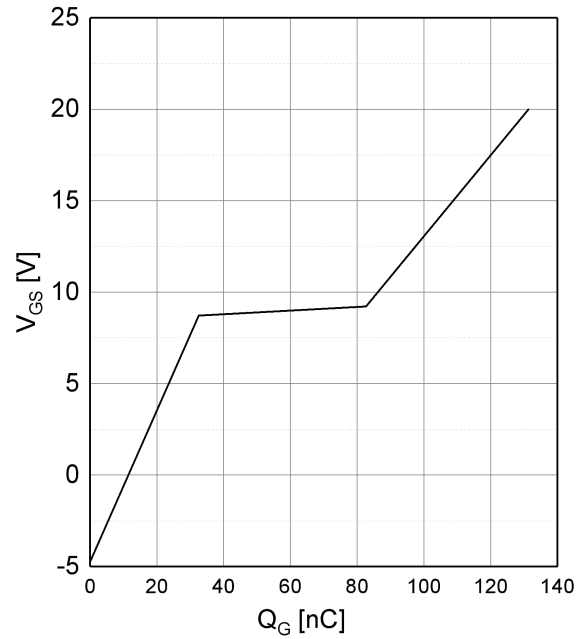
Body Diode Characteristics

$I_{DS}=f(V_{DS}), T_J=175^{\circ}\text{C}$



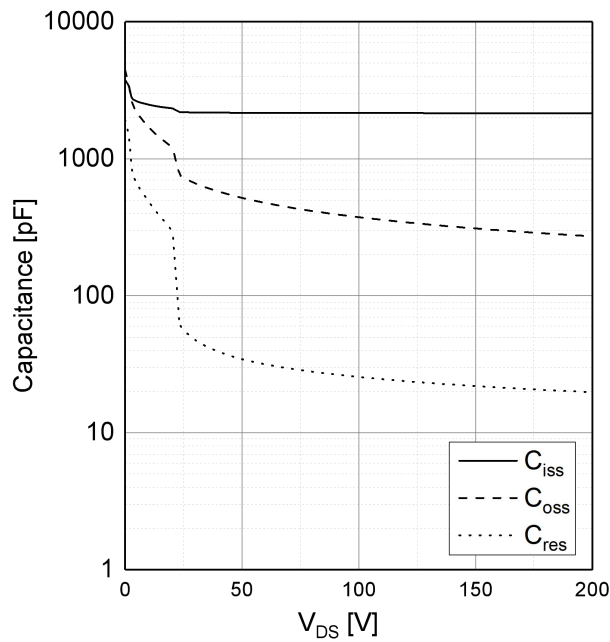
Gate Charge Characteristics

$V_{GS}=f(Q_G), I_{DS}=40\text{A}, V_{DS}=800\text{V}, T_J=25^{\circ}\text{C}$



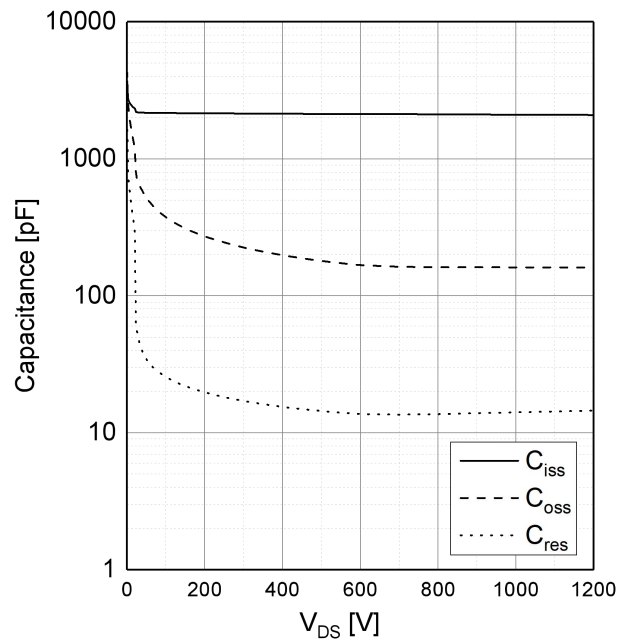
Capacitances vs Drain-Source Voltage (0-200V)

$C=f(V_{DS}), T_J=25^{\circ}\text{C}, V_{AC}=25\text{mV}, f=100\text{KHz}$



Capacitances vs Drain-Source Voltage (0-1200V)

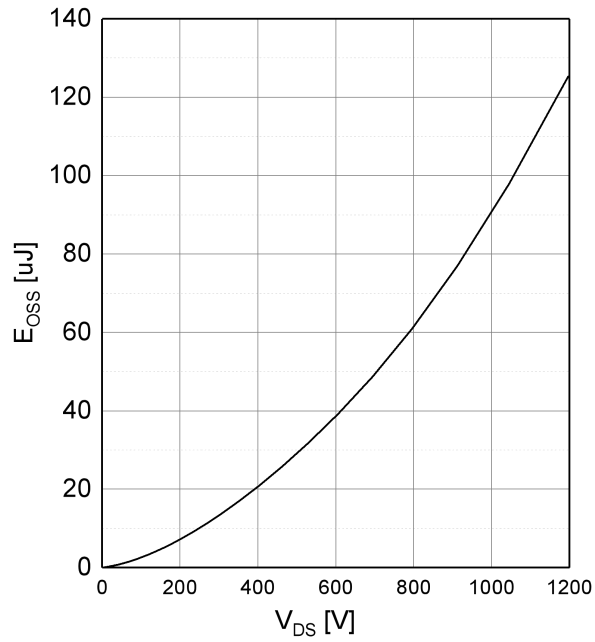
$C=f(V_{DS}), T_J=25^{\circ}\text{C}, V_{AC}=25\text{mV}, f=100\text{KHz}$





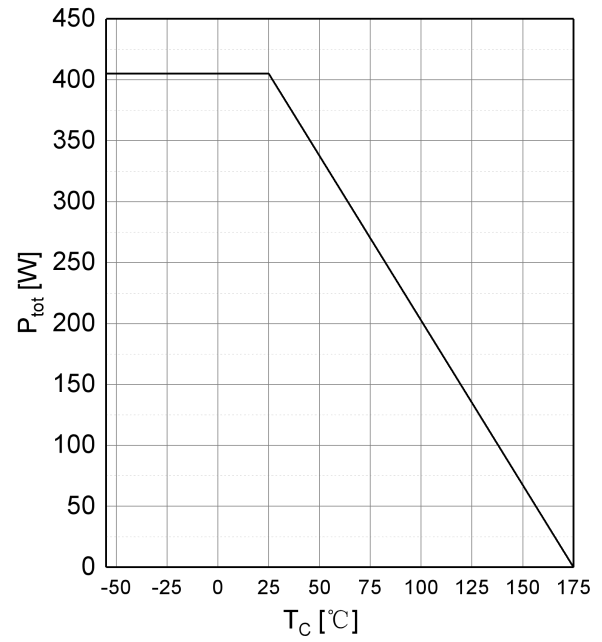
## Output Capacitor Stored Energy

$$E_{OSS} = f(V_{DS}), T_J = 25^{\circ}\text{C}$$



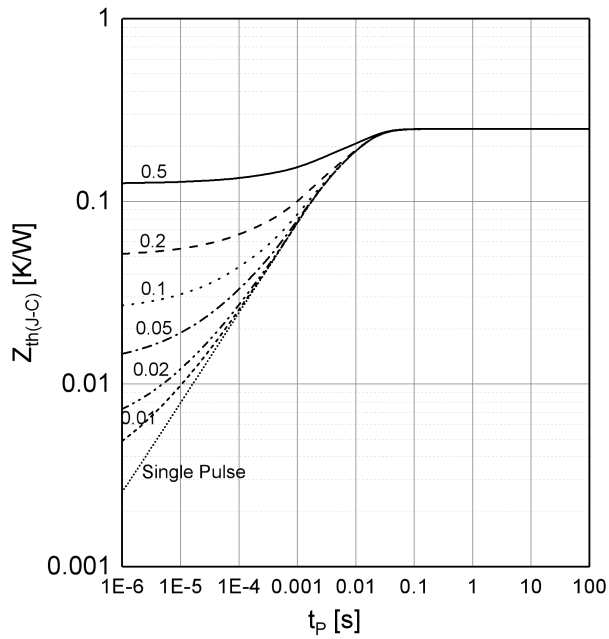
## Maximum Power Dissipation Derating

$$P_{tot} = f(T_C), T_J \leq 175^{\circ}\text{C}$$



## Transient Thermal Impedance (Junction to Case)

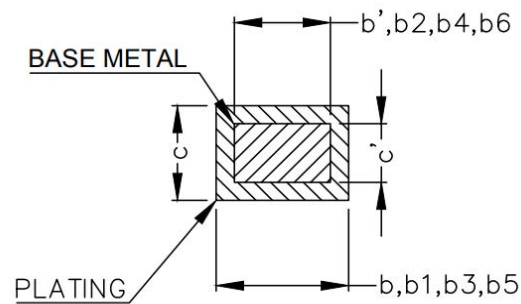
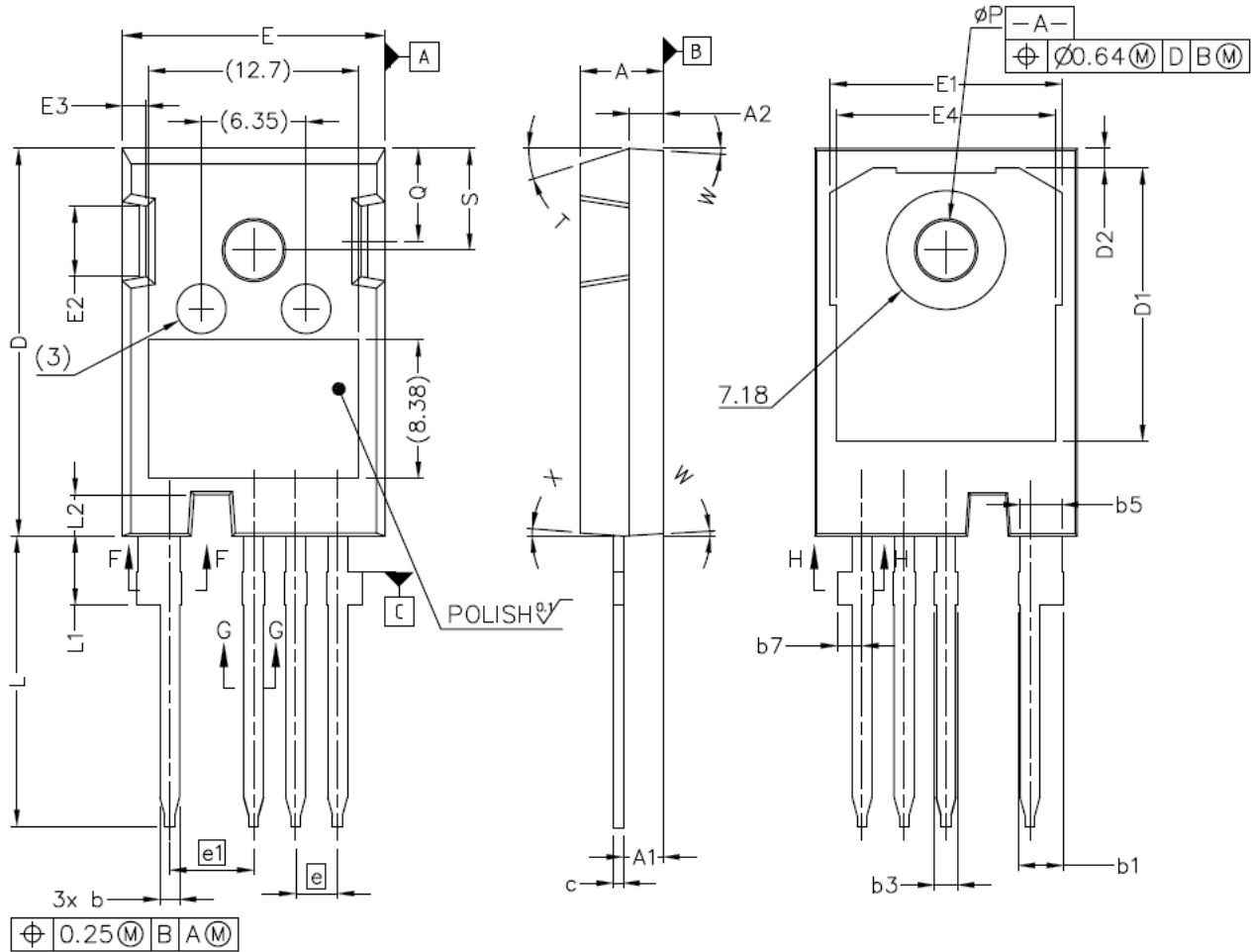
$$Z_{th(J-C)} = f(t), T_C = 25^{\circ}\text{C}$$





## Package Dimensions

Package T0247-4L



SECTION "F-F", "G-G" AND "H-H"  
SCALE: NONE



## Package Dimensions

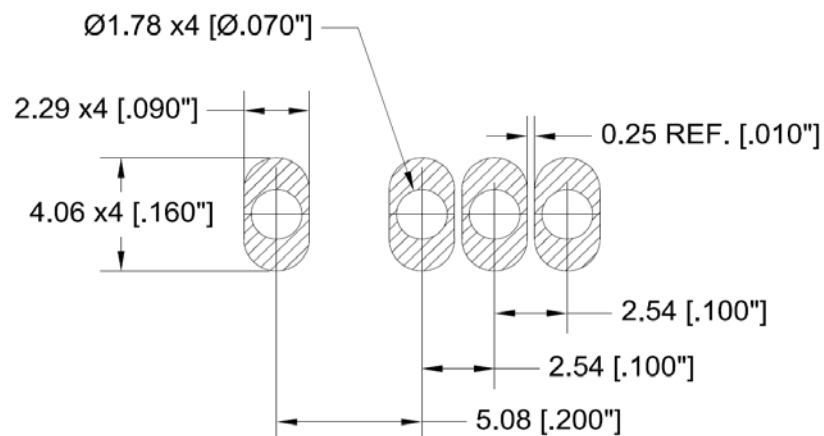
### Package T0247-4L

NOTE ;

1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
3. ALL DIMENSIONS ARE IN MILLIMETERS.  
ANGLES ARE IN DEGREES.
4. 'N' IS THE NUMBER OF TERMINAL POSITIONS

| SYM | MILLIMETERS |       |
|-----|-------------|-------|
|     | MIN         | MAX   |
| A   | 4.83        | 5.21  |
| A1  | 2.29        | 2.54  |
| A2  | 1.91        | 2.16  |
| b`  | 1.07        | 1.28  |
| b   | 1.07        | 1.33  |
| b1  | 2.39        | 2.94  |
| b2  | 2.39        | 2.84  |
| b3  | 1.07        | 1.60  |
| b4  | 1.07        | 1.50  |
| b5  | 2.39        | 2.69  |
| b6  | 2.39        | 2.64  |
| b7  | 1.30        | 1.70  |
| c`  | 0.55        | 0.65  |
| c   | 0.55        | 0.68  |
| D   | 23.30       | 23.60 |
| D1  | 16.25       | 17.65 |
| D2  | 0.95        | 1.25  |
| E   | 15.75       | 16.13 |

| SYM | MILLIMETERS |       |
|-----|-------------|-------|
|     | MIN         | MAX   |
| E1  | 13.10       | 14.15 |
| E2  | 3.68        | 5.10  |
| E3  | 1.00        | 1.90  |
| E4  | 12.38       | 13.43 |
| e   | 2.54 BSC    |       |
| e1  | 5.08 BSC    |       |
| N*  | 4           |       |
| L   | 17.31       | 17.82 |
| L1  | 3.97        | 4.37  |
| L2  | 2.35        | 2.65  |
| Ø P | 3.51        | 3.65  |
| Q   | 5.49        | 6.00  |
| S   | 6.04        | 6.30  |
| T   | 17.5° REF.  |       |
| W   | 3.5° REF.   |       |
| X   | 4° REF.     |       |





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